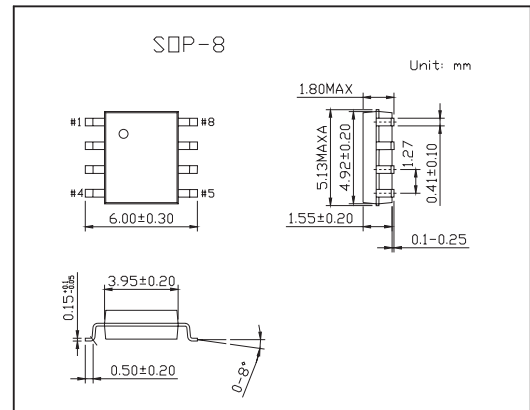
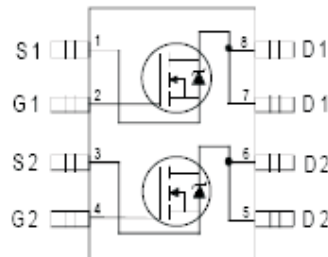


■ Features

- Advanced Process Technology
- Ultra Low On-Resistance
- Dual N and P Channel Mosfet
- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Fast Switching



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	N-Channel	P-Channel	Unit
Continuous Drain Current V _{GS} @ 10V Ta = 25°C	I _D	3.5	-2.3	A
Continuous Drain Current V _{GS} @ 10V Ta = 70°C	I _D	2.8	-1.8	
Pulsed Drain Current *1	I _{DM}	14	-10	
Power Dissipation @T _c = 25°C	P _D	2.0		W
Linear Derating Factor		0.016		W/°C
Peak Diode Recovery dv/dt *2	dv/dt	3.0	-3.0	V/ ns
Gate-to-Source Voltage	V _{GS}	±20		V
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to + 150		°C
Maximum Junction-to-Ambient*3	R _{θJA}	62.5		°C/W

*1 Repetitive rating; pulse width limited by max. junction temperature.

*2 N-Channel I_{SD} ≤ 3.5A, di/dt ≤ 90A/μs, V_{DD} ≤ V_{(BR)DSS}, T_J ≤ 150°C

P-Channel I_{SD} ≤ -2.3A, di/dt ≤ 90A/μs, V_{DD} ≤ V_{(BR)DSS}, T_J ≤ 150°C

*3 Surface mounted on FR-4 board, t ≤ 10sec.

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250 μ A	N-Ch	25		V
		V _{GS} = 0V, I _D = -250 μ A	P-Ch	-20		
Breakdown Voltage Temp. Coefficient	ΔV _{(BR)DSS} / ΔT _J	I _D = 1mA, Reference to 25°C	N-Ch	0.030		V/°C
		I _D = -1mA, Reference to 25°C	P-Ch	-0.015		
Static Drain-to-Source On-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 1.0A*1	N-Ch	0.083	0.10	Ω
		V _{GS} = 4.5V, I _D = 0.5A*1		0.14	0.16	
		V _{GS} = -10V, I _D = -1.0A*1	P-Ch	0.16	0.25	
		V _{GS} = -4.5V, I _D = -0.50A*1		0.30	0.40	
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μ A	N-Ch	1.0	3.0	V
		V _{DS} = V _{GS} , I _D = -250 μ A	P-Ch	-1.0	-3.0	
Forward Transconductance	g _{fs}	V _{DS} = 15V, I _D = 3.5A*1	N-Ch	4.3		S
		V _{DS} = -15V, I _D = -3.5A*1	P-Ch	3.1		
Drain-to-Source Leakage Current	I _{DSS}	V _{DS} = 20V, V _{GS} = 0V	N-Ch		2.0	μ A
		V _{DS} = -20V, V _{GS} = 0V	P-Ch		-2.0	
		V _{DS} = 20V, V _{GS} = 0V, T _J = 55°C	N-Ch		25	
		V _{DS} = -20V, V _{GS} = 0V, T _J = 55°C	P-Ch		-25	
Gate-to-Source Forward Leakage	I _{GSS}	V _{GS} = ±20V	N-Ch		±100	nA
			P-Ch		±100	
Total Gate Charge	Q _g	N-Channel I _D = 2.3A, V _{DS} = 12.5V, V _{GS} = 10V *1	N-Ch	9.4	27	nC
Gate-to-Source Charge	Q _{gs}	P-Channel	N-Ch	1.7		
			P-Ch	1.9		
Gate-to-Drain ("Miller") Charge	Q _{gd}	I _D = -2.3A, V _{DS} = -12.5V, V _{GS} = -10V *1	N-Ch	3.1		
			P-Ch	2.8		
Turn-On Delay Time	t _{d(on)}	N-Channel V _{DD} = 25V, I _D = 1.0A, R _G = 6.0 Ω	N-Ch	7.0		ns
Rise Time	t _r	P-Channel R _D = 25 Ω *1	N-Ch	9.0		
			P-Ch	13		
Turn-Off Delay Time	t _{d(off)}	V _{DD} = -25V, I _D = -1.0A, R _G = 6.0 Ω R _D = 25 Ω 1*1	N-Ch	45		
			P-Ch	45		
Fall Time	t _f		N-Ch	25		
			P-Ch	37		
Internal Drain Inductace	L _D	Between lead, 6mm(0.25in.) from packing and center of die contact	N-Ch	4.0		
			P-Ch	4.0		
Internal Source Inductance	L _S		N-Ch	6.0		
			P-Ch	6.0		
Input Capacitance	C _{iss}	N-Channel V _{GS} = 0V, V _{DS} = 15V, f = 1.0MHz *1	N-Ch	330		pF
			P-Ch	290		
Output Capacitance	C _{oss}	P-Channel	N-Ch	250		
			P-Ch	210		
Reverse Transfer Capacitance	C _{rss}	V _{GS} = 0V, V _{DS} = -15V, f = 1.0MHz *1	N-Ch	61		
			P-Ch	67		

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit		
Continuous Source Current (Body Diode)	Is		N-Ch		2.0	A		
			P-Ch		-2.0			
Pulsed Source Current (Body Diode) *2	ISM		N-Ch		14			
			P-Ch		-9.2			
Diode Forward Voltage	VSD	TJ = 25°C, Is = 1.3A, VGS = 0V*1	N-Ch		1.2	V		
		TJ = 25°C, Is = -1.3A, VGS = 0V*1	P-Ch		-1.2			
Reverse Recovery Time	trr	N-Channel TJ = 25°C, IF = 1.3A, di/dt = 100A/μs*1	N-Ch		36	54	ns	
			P-Ch		69	100		
Reverse RecoveryCharge	Qrr		P-Channel TJ = 25°C, IF = -1.3A, di/dt = -100A/μs*1	N-Ch		41	75	nC
				P-Ch		90	180	
Forward Turn-On Time	ton	Intrinsic turn-on time is negligible (turn-on is dominated by Ls+Ld)		N-Ch				
				P-Ch				

*1 Pulse width ≤ 300 μs; duty cycle ≤ 2%.

*2 Repetitive rating; pulse width limited by max. junction temperature.